Dynamic SIMS

SIMS: CAMECA IMS-6f

O$_2^+$ 1.25keV impact energy
and
Cs$^+$ 14.5keV impact energy
Raster size 180µm x 180µm to 220µm x 220µm
60µm optically gated analyzed area
Impurities
Interstitials
NRA H Depth Profile

![Graph showing NRA hydrogen depth profiling on Nb samples with depth and hydrogen concentration on the y-axis and depth in micrometers on the x-axis. The graph compares samples #2, #3, #4, #5, #6, #9, and #10 baked at different temperatures: 90°C, 105°C, 120°C, and 140°C for 48 hours.](image-url)